

State of Art in eSRAM design and validation flow

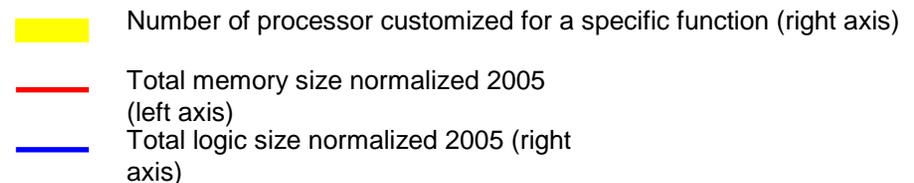
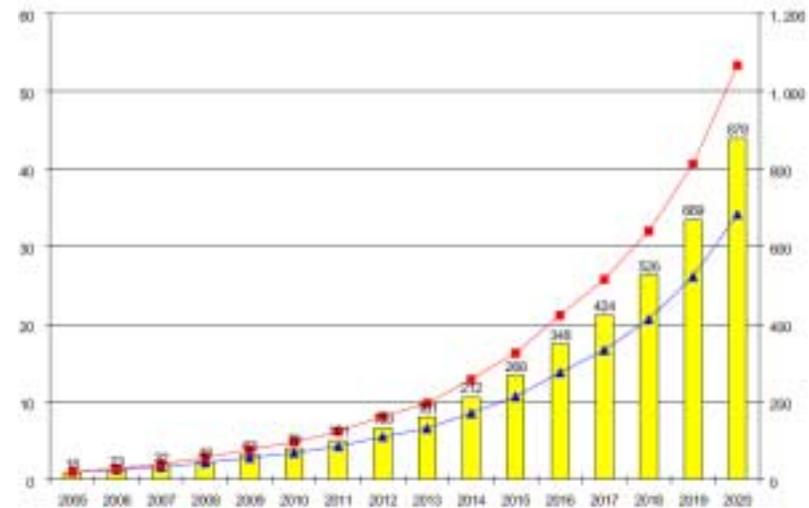
Presentation of D1.1 document

Outline

- ▣ Introduction: eSRAM in SoC market
- ▣ General overview of the eSRAM design
- ▣ Design and verification of transistor based design
 - Design and verification of critical path
 - Design and verification of full cut
- ▣ Design and verification of functional view
- ▣ Overview of the weaknesses of today flow

Introduction eSRAM in SoC market

- ▣ Number of embedded memory increases with the complexity of the SoC (>400 items).
- ▣ Performances and area are key questions for the cost and the performances of the final product.
- ▣ Embedded memories are mainly eSRAM



ITRS 2005 System Drivers

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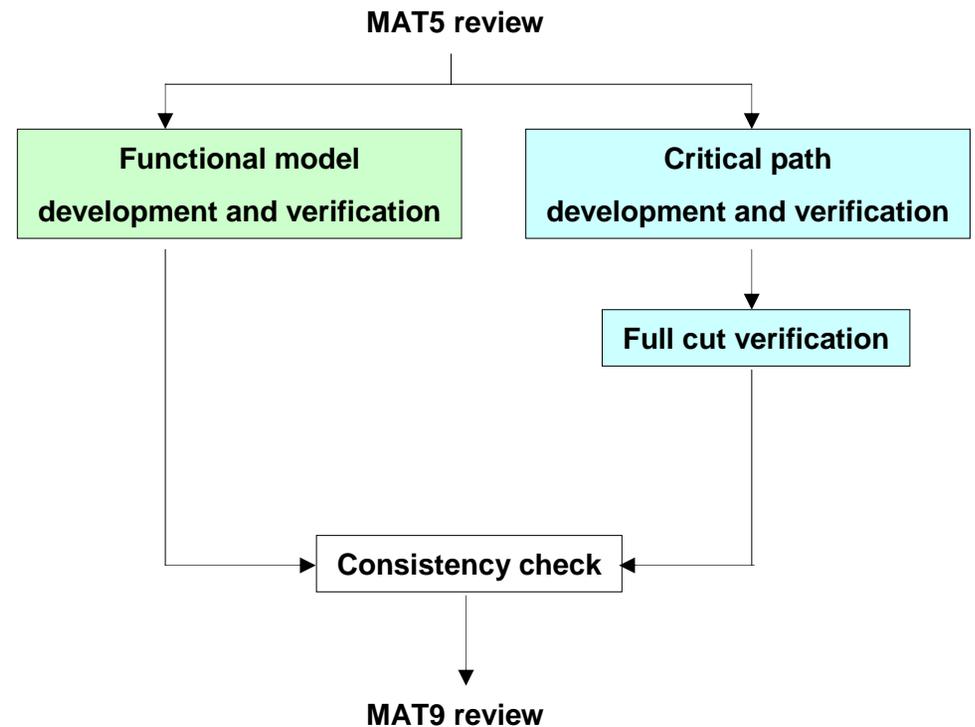
General overview of the eSRAM design Quality items

Quality steps	Description	Development processes to be achieved		
		Specifications	CAD flow	Silicon
MAT5	Memory specification frozen Customers identified	X		
MAT9	Memory compiler ready Basic views built and checked	X	Basic views generated	
MAT10	Additional derived views are generated	X	All views generated	
MAT20	Design successfully checked on silicon	X	All views generated	Functional tests done
MAT30	Design successfully checked on all temperature ranges.	X	All views generated	Reliability test done

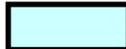
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General overview of the eSRAM design Design flow

- ▣ HDL and Transistor worlds are independent: they are compared at the end of the flow
- ▣ Transistor based development are spit into 2 steps
 - Tune the model on a simplified eSRAM
 - Compare the results with the real eSRAM



 HDL world

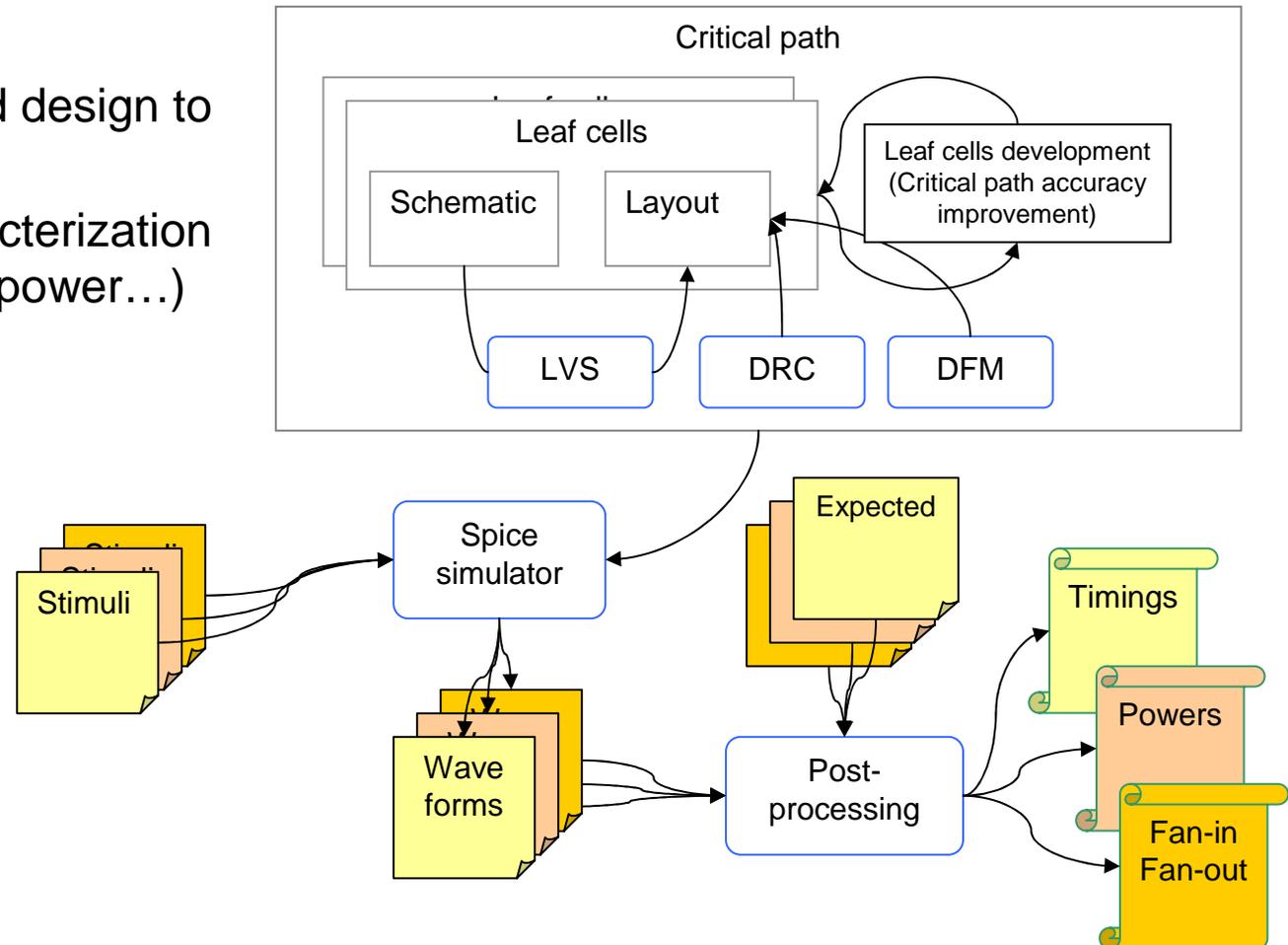
 Transistor world

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Transistor based design

Design and verification of critical path

- Working on simplified design to win run time
- Perform all the characterization on this design (timing, power...)

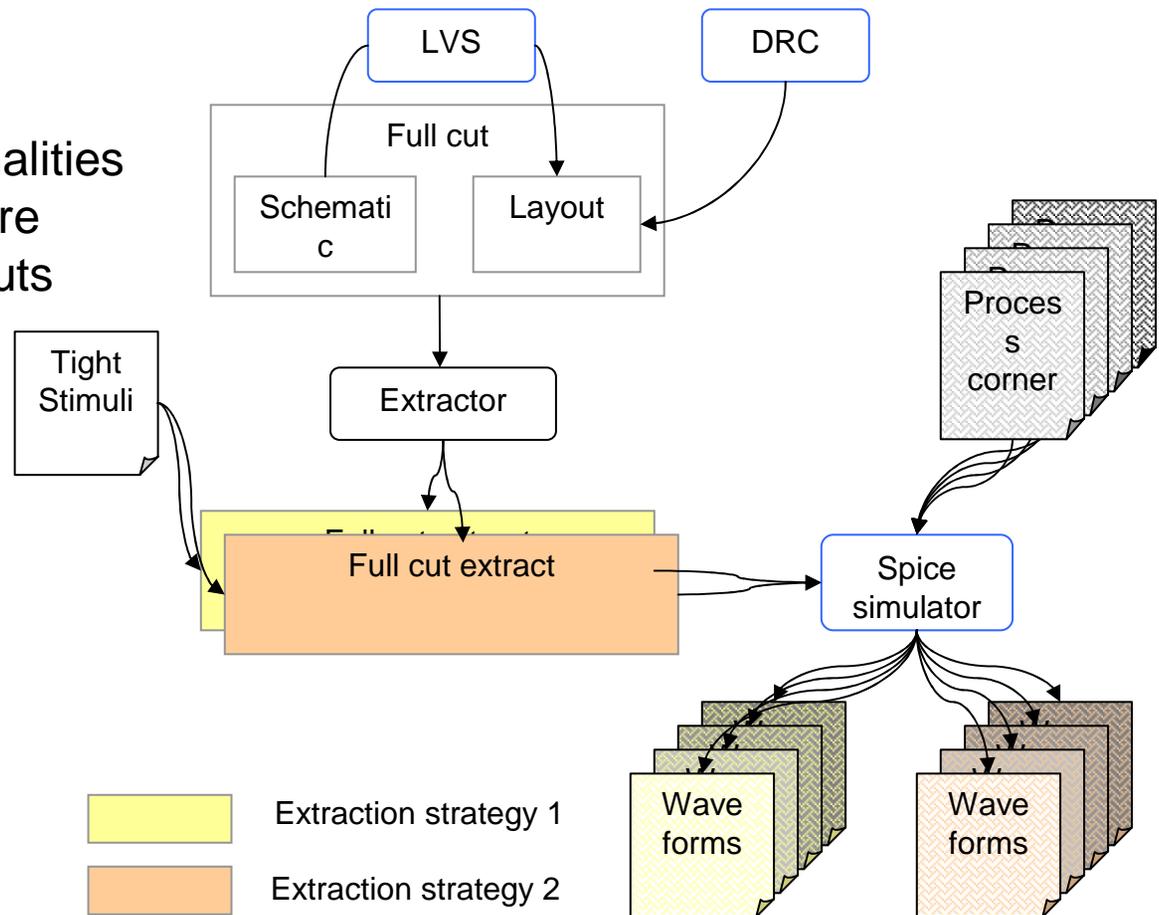


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Transistor based design

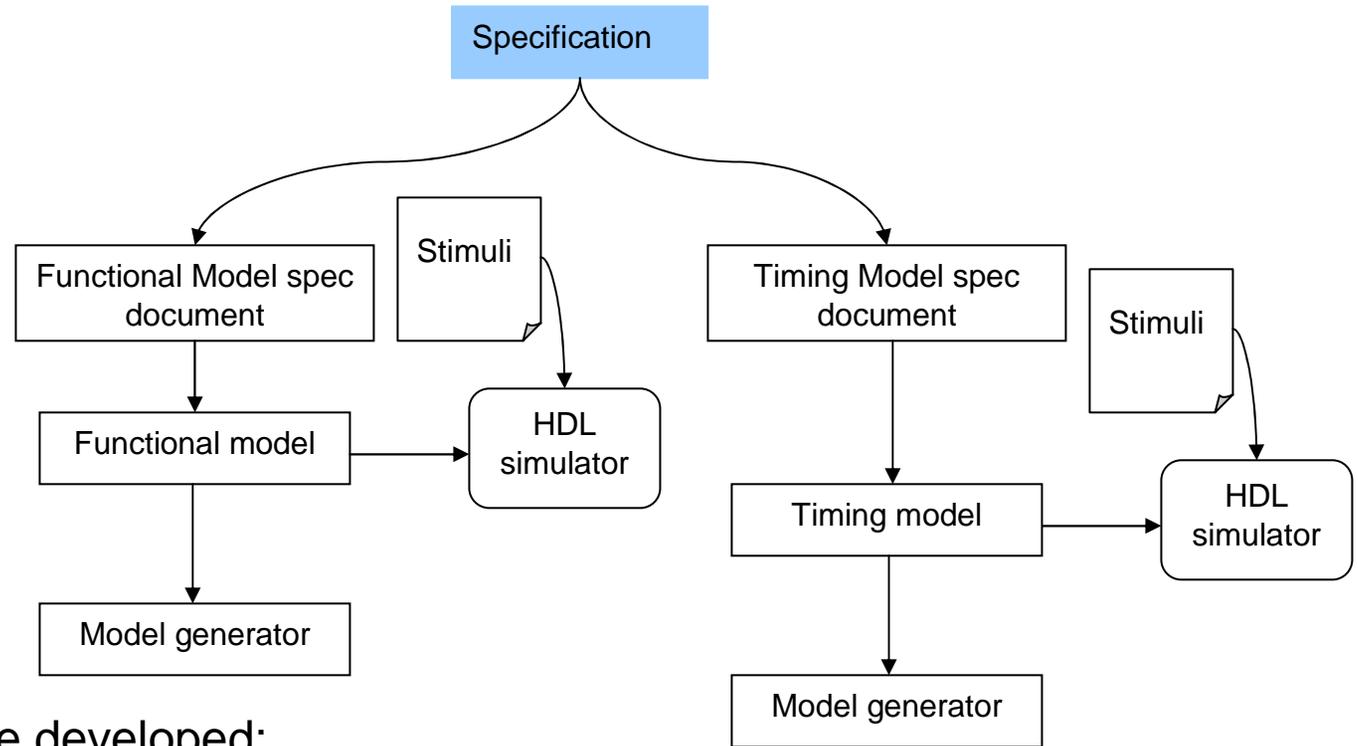
Design and verification of full cut

Performances and functionalities found with the critical path are checked in on corner full-cuts



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Design and verification of functional view



- ▣ Two models are developed:
 - Timed
 - Functional
- ▣ Use digital verification strategies

Overview of the weaknesses of today flow (1/2)

Transistor based design flow

- Use only transistor based simulation
 - Cannot cover all cases
- Design and vectors are developed by the same people
 - There is no cross-check performed with independent point of view
 - Timings are not optimum
 - All the paths are not checked
 - Debug at silicon must be avoided as soon as possible: very costly, very complex and very long

Overview of the weaknesses of today flow (2/2)

- ▣ Need timing study:

 - A kind of static timing analysis

- ▣ Need Functional analysis

 - A kind of property checking tool

- ▣ Good solution: Check functionalities with timings

 - There is no industrial solutions to check timings and functionalities in one shot